



TAOS Inc.

is now

ams AG

The technical content of this TAOS datasheet is still valid.

Contact information:

Headquarters:

ams AG
Tobelbaderstrasse 30
8141 Unterpremstaetten, Austria

Tel: +43 (0) 3136 500 0

e-Mail: ams_sales@ams.com

Please visit our website at www.ams.com







Features

- Digital Proximity Detector, LED Driver, and IR LED in a Single Optical Module
- Register Set- and Pin-Compatible with the TMD2671 Series
- Proximity Detection
 - Reduced Proximity Count Variation *
 - Programmable Offset Control Register *
 - Saturation Indicator *
 - Programmable Integration Time and Offset
 - Current Sink Driver for IR LED
 - 16,000:1 Dynamic Range
- Maskable Proximity Interrupt
 - Programmable Upper and Lower Thresholds with Persistence Filter
- Power Management
 - Low Power 2.2 μA Sleep State with User-Selectable Sleep-After-Interrupt Mode *
 - 90 μA Wait State with Programmable Wait Time from 2.7 ms to > 8 seconds
- I²C Fast Mode Compatible Interface
 - Data Rates up to 400 kbit/s
 - Input Voltage Levels Compatible with V_{DD} or 1.8-V Bus
- 3.94 mm × 2.36 mm × 1.35 mm Package

PACKAGE

Package Drawing is Not to Scale

Applications

- Mobile Handset Touchscreen Control and Automatic Speakerphone Enable
- Mechanical Switch Replacement
- Paper Alignment

End Products and Market Segments

- Mobile Handsets, Tablets, Laptops and HDTVs
- White Goods
- Toys
- Digital Signage
- Printing

Description

The TMD2672 family of devices provides a complete proximity detection system and digital interface logic in a single 8-pin surface mount module. The devices are register-set and pin-compatible with the TMD2671 series and includes new and improved proximity detection features. The proximity detection includes improved signal-to-noise and accuracy. A proximity offset register allows compensation for optical system crosstalk between the IR LED and the sensor. To prevent false proximity data measurement readings, a proximity saturation indicator bit signals that the internal analog circuitry has reached saturation. Interrupts have been enhanced with the addition of a sleep-on-interrupt feature that also allows for a single cycle operation. The device internal state machine provides the ability to put the device in a low-power mode in between proximity measurements, providing very low average power consumption.

The proximity detection system includes an LED driver and an IR LED, which are factory trimmed to eliminate the need for end-equipment calibration due to component variations.

1

MODULE-8 (TOP VIEW)

V_{DD} 1 8 SDA

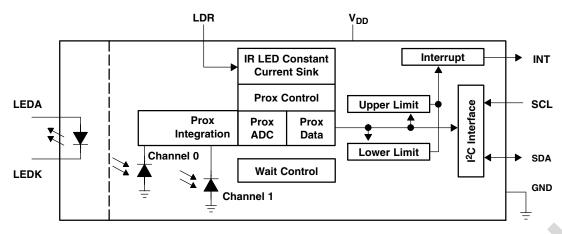
SCL 2 7 INT

GND 3 6 LDR

LEDA 4 5 LEDK

^{*} New or improved feature

Functional Block Diagram



Detailed Description

A fully integrated proximity detection solution is provided with an 850-nm IR LED, LED driver circuit, and proximity detection engine. An internal LED driver (LDR) pin, is externally connected to the LED cathode (LEDK) to provide a controlled LED sink current. This is accomplished with a proprietary current calibration technique that accounts for all variances in silicon, optics, package, and most important, IR LED output power. This eliminates or greatly reduces the need for factory calibration that is required for most discrete proximity sensor solutions. The device is factory calibrated to achieve a proximity count reading at a specified distance with a specific number of pulses. In use, the number of proximity LED pulses can be programmed from 1 to 255 pulses, which allows different proximity distances to be achieved. Each pulse has a 16-μs period, with a 7.2-μs on time.

The device provides a separate pin for level-style interrupts. When interrupts are enabled and a pre-set value is exceeded, the interrupt pin is asserted and remains asserted until cleared by the controlling firmware. The interrupt feature simplifies and improves system efficiency by eliminating the need to poll a sensor for a proximity value. An interrupt is generated when the value of a proximity conversion exceeds either an upper or lower threshold. In addition, a programmable interrupt persistence feature allows the user to determine how many consecutive exceeded thresholds are necessary to trigger an interrupt.



Terminal Functions

TERMINAL			PERCENTAGE	
NAME	NO.	TYPE	DESCRIPTION	
GND	3		Power supply ground. All voltages are referenced to GND.	
INT	7	0	Interrupt — open drain (active low).	
LDR	6	0	LED driver input for proximity IR LED, constant current source LED driver.	
LEDA	4		LED anode.	
LEDK	5		LED cathode. Connect to LDR pin when using internal LED driver circuit.	.
SCL	2	I	I ² C serial clock input terminal — clock signal for I ² C serial data.	
SDA	8	I/O	I ² C serial data I/O terminal — serial data I/O for I ² C .	
V_{DD}	1		Supply voltage.	

Available Options

DEVICE	ADDRESS	LEADS	INTERFACE DESCRIPTION	ORDERING NUMBER
TMD26721	0x39	Module-8	I ² C Vbus = V _{DD} Interface	TMD26721
TMD26723	0x39	Module-8	I ² C Vbus = 1.8 V Interface	TMD26723
TMD26725 [†]	0x29	Module-8	I ² C Vbus = V _{DD} Interface	TMD26725
TMD26727 [†]	0x29	Module-8	I ² C Vbus = 1.8 V Interface	TMD26727

[†] Contact TAOS for availability.

Absolute Maximum Ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{DD} (Note 1)	3.8 V
Input terminal voltage	
Output terminal voltage (except LDR)	
Output terminal voltage (LDR)	
Output terminal current (except LDR)	–1 mA to 20 mA
Storage temperature range, T _{stq}	–40°C to 85°C
ESD tolerance, human body model	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages are with respect to GND.

Recommended Operating Conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{DD}	2.6	3	3.6	V
Supply voltage accuracy, V _{DD} total error including transients	-3		3	%
Operating free-air temperature, T _A (Note 2)	-30		85	°C

NOTE 2: While the device is operational across the temperature range, functionality will vary with temperature. Specifications are stated only at 25°C unless otherwise noted.



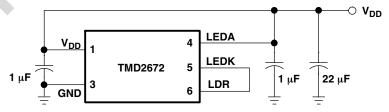
Operating Characteristics, V_{DD} = 3 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		Active — LDR pulse off		195	250	
I_{DD}	Supply current	Wait state		90		μΑ
		Sleep state — no I ² C activity		2.2	4	
v	INIT CDA autout laurustana	3 mA sink current	0		0.4	V
V_{OL}	INT, SDA output low voltage	6 mA sink current	0		0.6	V
I _{LEAK}	Leakage current, SDA, SCL, INT pins		-5		5	μΑ
I _{LEAK}	Leakage current, LDR pin		-5		5	μΑ
v	COL CDA is not bish walks as	TMD26721	0.7 V _{DD}			77
V_{IH}	SCL, SDA input high voltage	TMD26723	1.25			V
v	COL CDA input law valtage	TMD26721			0.3 V _{DD}	V
V_{IL}	SCL, SDA input low voltage	TMD26723			0.54	٧

Proximity Characteristics, $V_{DD} = V_{LEDA} = 3 \text{ V}$, $T_A = 25^{\circ}\text{C}$, PEN = 1 (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
I _{DD}	Supply current	LED On		3		mA
		LED On, PDRIVE = 0		100		
١.	1504 (41)	LED On, PDRIVE = 1		50		
I _{LEDA}	LEDA current (Note 1)	LED On, PDRIVE = 2		25		mA
		LED On, PDRIVE = 3		12.5		
PTIME	ADC conversion steps		1		256	steps
PTIME	ADC conversion time	PTIME = 0xFF (= 1 conversion step)	2.58	2.73	2.9	ms
PTIME	ADC counts per step	PTIME = 0xFF (= 1 conversion step)	0		1023	counts
PPULSE	LED pulses (Note 5)		0		255	pulses
LED On	LED pulse width	PPULSE = 1, PDRIVE = 0		7.3		μs
	LED pulse period	PPULSE = 2, PDRIVE = 0		16.0		μs
	Proximity response, no target (offset)	PPULSE = 8, PDRIVE = 0, PGAIN = 4×, (Note 2)		100		counts
	Prox count, 100-mm target (Note 3)	73 mm × 83 mm, 90% reflective Kodak Gray Card, PGAIN = 4×, PPULSE = 8, PDRIVE = 0, PTIME = 0xFF (Note 4)	450	520	590	counts

- NOTES: 1. Value is factory-adjusted to meet the Prox count specification. Considerable variation (relative to the typical value) is possible after
 - 2. Proximity offset varies with power supply characteristics and noise.
 - 3. I_{LEDA} is factory calibrated to achieve this specification. Offset and crosstalk directly sum with this value and is system dependent.
 - 4. No glass or aperture above the module. Tested value is the average of 5 consecutive readings.
 - 5. These parameters are ensured by design and characterization and are not 100% tested.
 - 6. Proximity test was done using the following circuit. See the Application Information: Hardware section for recommended application circuit.



ADVANCED OPTOELECTRONIC SOLUTIONS® www.taosinc.com

IR LED Characteristics, V_{DD} = 3 V, T_A = 25°C

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V_{F}	Forward Voltage	I _F = 20 mA		1.4	1.5	V
V_{R}	Reverse Voltage	$I_R = 10 \mu A$	5			V
Po	Radiant Power	I _F = 20 mA	4.5			mW
λ_p	Peak Wavelength	I _F = 20 mA		850		nm
Δ_{λ}	Spectral Radiation Bandwidth	I _F = 20 mA		40		nm
T_{R}	Optical Rise Time	I _F = 100 mA, T _W = 125 ns, duty cycle = 25%		20	40	ns
T_F	Optical Fall Time	I _F = 100 mA, T _W = 125 ns, duty cycle = 25%		20	40 (ns

Wait Characteristics, V_{DD} = 3 V, T_A = 25°C, WEN = 1 (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
Wait time	WTIME = 0xFF (= 1 wait step)	*	2.73	2.9	ms
Wait steps		1		256	steps

AC Electrical Characteristics, $V_{DD} = 3 \text{ V}$, $T_A = 25^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER†	TEST CONDITIONS	MIN	TYP MAX	UNIT
f _(SCL)	Clock frequency (I ² C only)		0	400	kHz
t _(BUF)	Bus free time between start and stop condition		1.3		μs
t _(HDSTA)	Hold time after (repeated) start condition. After this period, the first clock is generated.		0.6		μs
t _(SUSTA)	Repeated start condition setup time	N. (%)	0.6		μs
t _(SUSTO)	Stop condition setup time		0.6		μs
t _(HDDAT)	Data hold time		0		μs
t _(SUDAT)	Data setup time		100		ns
t _(LOW)	SCL clock low period		1.3		μs
t _(HIGH)	SCL clock high period		0.6		μs
t _F	Clock/data fall time	,		300	ns
t _R	Clock/data rise time			300	ns
C _i	Input pin capacitance			10	pF

 $[\]ensuremath{^\dagger}$ Specified by design and characterization; not production tested.



PARAMETER MEASUREMENT INFORMATION

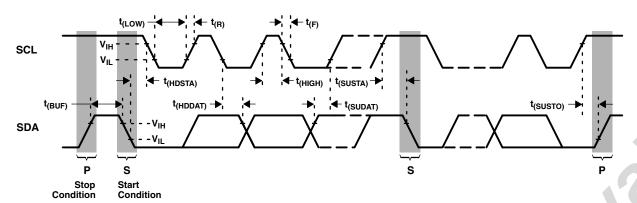
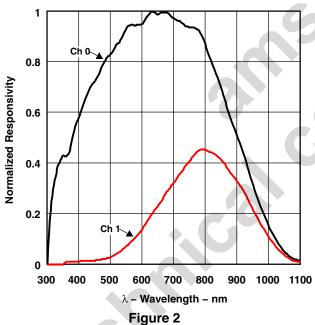


Figure 1. Timing Diagrams

TYPICAL CHARACTERISTICS

SPECTRAL RESPONSIVITY



NORMALIZED RESPONSIVITY

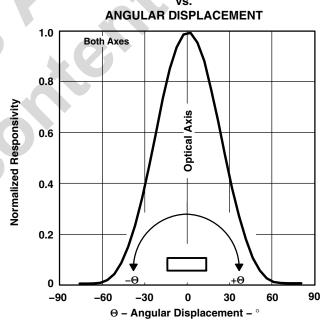
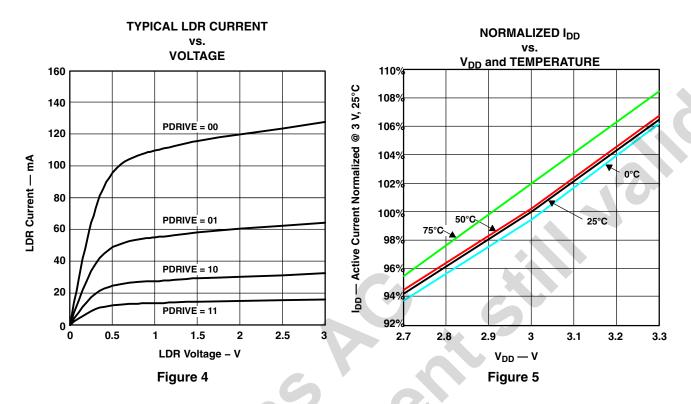


Figure 3

TYPICAL CHARACTERISTICS



PRINCIPLES OF OPERATION

System State Machine

An internal state machine provides system control of the proximity detection and power management features of the device. At power up, an internal power-on-reset initializes the device and puts it in a low-power Sleep state.

When a start condition is detected on the I²C bus, the device transitions to the Idle state where it checks the Enable register (0x00) PON bit. If PON is disabled, the device will return to the Sleep state to save power. Otherwise, the device will remain in the Idle state until a proximity function is enabled. Once enabled, the device will execute the Prox and Wait states in sequence as indicated in Figure 6. Upon completion and return to Idle, the device will automatically begin a new prox-wait cycle as long as PON and PEN are enabled.

If the Prox function generates an interrupt and the Sleep-After-Interrupt (SAI) feature is enabled the device will transition to the Sleep state and remain in a low-power mode until an I²C command is received. See the Interrupts section for additional information.

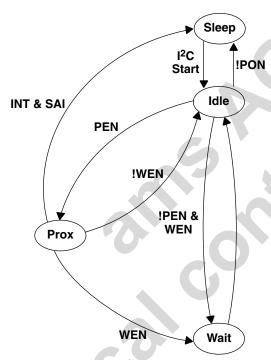


Figure 6. Simplified State Diagram

Proximity Detection

Proximity detection is accomplished by measuring the amount of IR energy, from the internal IR LED, reflected off an object to determine its distance. The internal proximity IR LED is driven by the integrated proximity LED current driver as shown in Figure 7.

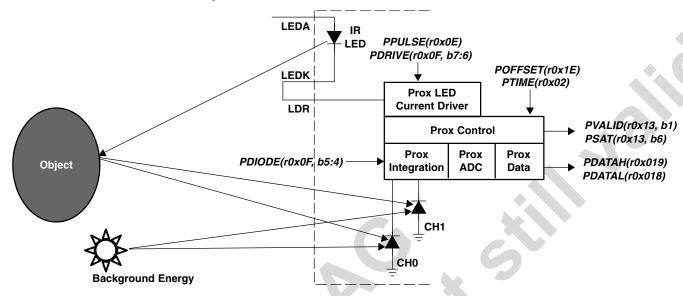


Figure 7. Proximity Detection

The LED current driver, output on the LDR terminal, provides a regulated current sink that eliminates the need for an external current limiting resistor. PDRIVE sets the drive current to one of four selectable levels.

Referring to the Detailed State Machine figure, the LED current driver pulses the IR LED as shown in Figure 8 during the Prox Accum state. Figure 8 also illustrates that the LED On pulse has a fixed width of $7.3~\mu s$ and period of $16.0~\mu s$. So, in addition to setting the proximity drive current, 1 to 255 proximity pulses (PPULSE) can be programmed. When deciding on the number of proximity pulses, keep in mind that the signal increases proportionally to PPULSE, while noise increases by the square root of PPULSE.

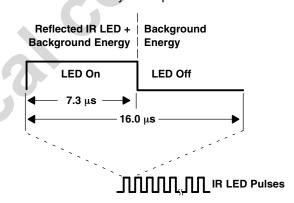


Figure 8. Proximity LED Current Driver Waveform

Figure 7 illustrates light rays emitting from the internal IR LED, reflecting off an object, and being absorbed by the CH0 and CH1 photodiodes. The proximity diode selector (PDIODE) determines which of the two photodiodes is used for a given proximity measurement. Note that neither photodiode is selected when the device first powers up, so PDIODE must be set for proximity detection to work.



TMD2672 DIGITAL PROXIMITY DETECTOR

TAOS149C - AUGUST 2012

Referring again to Figure 8, the reflected IR LED and the background energy is integrated during the LED On time, then during the LED Off time, the integrated background energy is subtracted from the LED On time energy, leaving the IR LED energy to accumulate from pulse to pulse. During LED On time integration, the proximity saturation bit in the Status register (0x13) will be set if the integrator saturates. This condition can occur if the proximity gain is set too high for the lighting conditions, such as in the presence of bright sunlight. Once asserted, PSAT will remain set until a special function proximity interrupt clear command is received from the host (see command register).

After the programmed number of proximity pulses have been generated, the proximity ADC converts and scales the proximity measurement to a 16-bit value, then stores the result in two 8-bit proximity data (PDATAx) registers. ADC scaling is controlled by the proximity ADC conversion time (PTIME) which is programmable from 1 to 256 2.73-ms time units. However, depending on the application, scaling the proximity data will equally scale any accumulated noise. Therefore, in general, it is recommended to leave PTIME at the default value of one 2.73-ms ADC conversion time (0xFF).

In many practical proximity applications, a number of optical system and environmental conditions can produce an offset in the proximity measurement result. To counter these effects, a proximity offset (POFFSET) is provided which allows the proximity data to be shifted positive or negative. Additional information on the use of the proximity offset feature is provided in available TAOS application notes.

Once the first proximity cycle has completed, the proximity valid (PVALID) bit in the Status register will be set and remain set until the proximity detection function is disabled (PEN).

For additional information on using the proximity detection function behind glass and for optical system design guidance, please see available TAOS application notes.



Interrupts

The interrupt feature simplifies and improves system efficiency by eliminating the need to poll the sensor for proximity values outside a user-defined range. While the interrupt function is always enabled and its status is available in the Status register (0x13), the output of the interrupt state can be enabled using the proximity interrupt enable (PIEN) field in the Enable register (0x00).

Two 16-bit interrupt threshold registers allow the user to set limits below and above a desired proximity range. An interrupt can be generated when the proximity data (PDATA) falls below the proximity interrupt low threshold (PILTx) or exceeds the proximity interrupt high threshold (PIHTx).

It is important to note that the thresholds are evaluated in sequence, first the low threshold, then the high threshold. As a result, if the low threshold is set above the high threshold, the high threshold is ignored and only the low threshold is evaluated.

To further control when an interrupt occurs, the device provides an interrupt persistence feature. The persistence filter allows the user to specify the number of consecutive out-of-range proximity occurrences before an interrupt is generated. The persistence filter register (0x0C) allows the user to set the proximity persistence filter (PPERS) values. See the persistence filter register for details on the persistence filter values. Once the persistence filter generates an interrupt, it will continue until a special function interrupt clear command is received (see Command register).

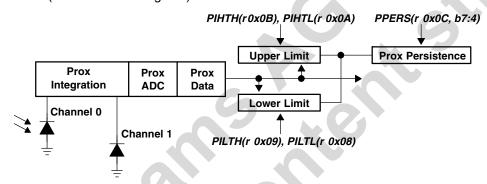


Figure 9. Programmable Interrupt



State Diagram

The system state machine shown in Figure 6 provides an overview of the states and state transitions that provide system control of the device. This section highlights the programmable features that affect the state machine cycle time, and provides details to determine system level timing.

When the proximity detection feature is enabled (PEN), the state machine transitions through the Prox Init, Prox Accum, Prox Wait, and Prox ADC states. The Prox Init and Prox Wait times are a fixed 2.73 ms, whereas the Prox Accum time is determined by the number of proximity LED pulses (PPULSE) and the Prox ADC time is determined by the integration time (PTIME). The formulas to determine the Prox Accum and Prox ADC times are given in the associated boxes in Figure 10. If an interrupt is generated as a result of the proximity cycle, it will be asserted at the end of the Prox ADC state and transition to the Sleep state if SAI is enabled.

When the power management feature is enabled (WEN), the state machine will transition in turn to the Wait state. The wait time is determined by WLONG, which extends normal operation by 12× when asserted, and WTIME. The formula to determine the wait time is given in the box associated with the Wait state in Figure 10.

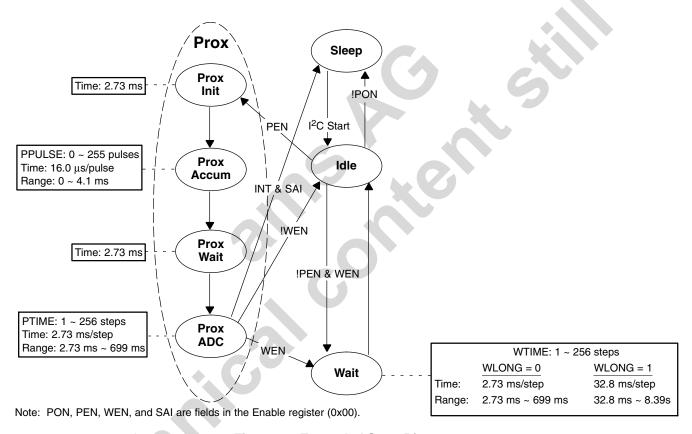


Figure 10. Expanded State Diagram

Power Management

Power consumption can be managed with the Wait state because the wait state consumes only 90 μ A of I_{DD} current. An example of the power management feature is shown in Table 1. With the assumptions provided in the example, the average I_{DD} is estimated to be 157 μ A.

Table 1. Power Management

SYSTEM STATE MACHINE STATE	PROGRAMMABLE PARAMETER	PROGRAMMED VALUE	DURATION	TYPICAL CURRENT
Prox Init			2.73 ms	0.195 mA
Prox Accum	PPULSE	0x04	0.064 ms	
Prox Accum – LED On			0.029 ms (Note 1)	103 mA
Prox Accum – LED OFF			0.035 ms (Note 2)	0.195 mA
Prox Wait			2.73 ms	0.195 mA
Prox ADC	PTIME	0xFF	2.73 ms	0.195 mA
	WTIME	0xEE		
Wait	WLONG	0	49.2 ms	0.090 mA

NOTES: 1. Prox Accum – LED On time = $7.3 \,\mu s$ per pulse \times 4 pulses = $29.3 \,\mu s$ = $0.029 \,m s$

2. Prox Accum – LED Off time = 8.7 μ s per pulse \times 4 pulses = 34.7 μ s = 0.035 ms

Average I_{DD} Current = ((2.73 × 0.195) + (0.029 × 103) + (0.035 x 0.195) + (2 x 2.73 x 0.195) + (49.2 × 0.090)) / 57.45 \approx 157 μ A

Keeping with the same programmed values as the example, Table 2 shows how the average I_{DD} current is affected by the Wait state time, which is determined by WEN, WTIME, and WLONG. Note that the worst-case current occurs when the Wait state is not enabled.

Table 2. Average IDD Current

WEN	WTIME	WLONG	WAIT STATE	AVERAGE I _{DD} CURRENT
0	n/a	n/a	0 ms	556 μΑ
1	0xFF	0	2.73 ms	440 μΑ
1	0xEE	0	49.2 ms	157 μΑ
1	0x00	0	699 ms	99 μΑ
1	0x00	1	8389 ms	90 μΑ



I²C Protocol

Interface and control are accomplished through an I²C serial compatible interface (standard or fast mode) to a set of registers that provide access to device control functions and output data. The devices support the 7-bit I²C addressing protocol.

The I²C standard provides for three types of bus transaction: read, write, and a combined protocol (Figure 11). During a write operation, the first byte written is a command byte followed by data. In a combined protocol, the first byte written is the command byte followed by reading a series of bytes. If a read command is issued, the register address from the previous command will be used for data access. Likewise, if the MSB of the command is not set, the device will write a series of bytes at the address stored in the last valid command with a register address. The command byte contains either control information or a 5-bit register address. The control commands can also be used to clear interrupts.

The I²C bus protocol was developed by Philips (now NXP). For a complete description of the I²C protocol, please review the NXP I²C design specification at http://www.i2c-bus.org/references/.

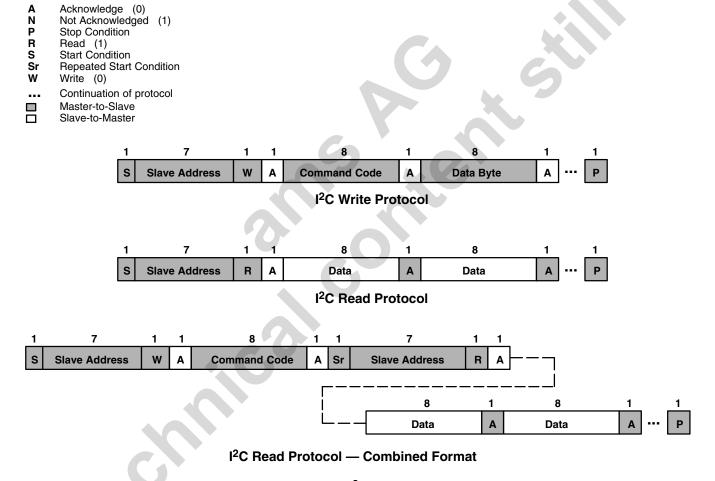


Figure 11. I²C Protocols

Register Set

The device is controlled and monitored by data registers and a command register accessed through the serial interface. These registers provide for a variety of control functions and can be read to determine results of the ADC conversions. The register set is summarized in Table 3.

Table 3. Register Address

ADDRESS	RESISTER NAME	R/W	REGISTER FUNCTION	RESET VALUE
	COMMAND	W	Specifies register address	0x00
0x00	ENABLE	R/W	Enables states and interrupts	0x00
0x02	PTIME	R/W	Proximity ADC time	0xFF
0x03	WTIME	R/W	Wait time	0xFF
0x08	PILTL	R/W	Proximity interrupt low threshold low byte	0x00
0x09	PILTH	R/W	Proximity interrupt low threshold high byte	0x00
0x0A	PIHTL	R/W	Proximity interrupt high threshold low byte	0x00
0x0B	PIHTH	R/W	Proximity interrupt high threshold high byte	0x00
0x0C	PERS	R/W	Interrupt persistence filter	0x00
0x0D	CONFIG	R/W	Configuration	0x00
0x0E	PPULSE	R/W	Proximity pulse count	0x00
0x0F	CONTROL	R/W	Control register	0x00
0x11	REVISION	R	Die revision number	Rev Num.
0x12	ID	R	Device ID	ID
0x13	STATUS	R	Device status	0x00
0x18	PDATAL	R	Proximity ADC low data register	0x00
0x19	PDATAH	R	Proximity ADC high data register	0x00
0x1E	POFFSET	R/W	Proximity Offset register	0x00

The mechanics of accessing a specific register depends on the specific protocol used. See the section on I²C protocols on the previous pages. In general, the COMMAND register is written first to specify the specific control/status register for following read/write operations.



Command Register

The command registers specifies the address of the target register for future write and read operations.

Table 4. Command Register

	,	ь	5	4	3	2	1	U	
COMMAND	COMMAND	TY	PE			ADD			Reset 0x00

FIELD	BITS	DESCRIPTION				
COMMAND	7	Select Command Register. Must write as 1 when addressing COMMAND register.				
TYPE	6:5	Selects type of tr	Selects type of transaction to follow in subsequent data transfers:			
		FIELD VALUE DESCRIPTION				
		00	Repeated byte protocol transaction			
		01	Auto-increment protocol transaction			
		10	Reserved — Do not use			
		11 Special function — See description below				
		Transaction type 00 will repeatedly read the same register with each data access. Transaction type 01 will provide an auto-increment function to read successive register bytes.				
ADD	4:0	specifies a specia	Address register/special function register. Depending on the transaction type, see above, this field eith specifies a special function command or selects the specific control-status-register for following write at read transactions:			
		FIELD VALUE	DESCRIPTION			
		00000	Normal — no action			
		00101	Proximity interrupt clear			
		Proximity Interrup	of Clear clears any pending proximity interrupt. This special function is self clearing.			

Enable Register (0x00)

The ENABLE register is used to power the device on/off, enable functions, and interrupts.

Table 5. Enable Register

7 3 2 6 5 0 Reset **ENABLE** Reserved SAI PIEN Reserved WEN PEN Reserved PON 0x00

FIELD	BITS	DESCRIPTION
Reserved	7	Reserved. Write as 0.
SAI	6	Sleep After Interrupt. 0 = not enabled, 1 = enabled
PIEN	5	Proximity interrupt mask. When asserted, permits proximity interrupts to be generated.
Reserved	4	Reserved. Write as 0.
WEN	3	Wait Enable. This bit activates the wait feature. Writing a 1 activates the wait timer. Writing a 0 disables the wait timer.
PEN	2	Proximity enable. This bit activates the proximity function. Writing a 1 enables proximity. Writing a 0 disables proximity.
Reserved	1	Reserved. Write as 0.
PON	0	Power ON. This bit activates the internal oscillator to permit the timers and ADC channel to operate. Writing a 1 activates the oscillator. Writing a 0 disables the oscillator.

Proximity Time Control Register (0x02)

The proximity timing register controls the integration time of the proximity ADC in 2.73 ms increments. Upon power up, the proximity time register is set to 0xFF. It is recommended that this register be programmed to a value of 0xFF (1 integration cycle).

Table 6. Proximity Time Control Register

FIELD	BITS		DESCRIPTION					
PTIME	7:0	VALUE	INTEG_CYCLES	TIME	MAX COUNT			
		0xFF	1	2.73 ms	1023			

Wait Time Register (0x03)

Wait time is set 2.73 ms increments unless the WLONG bit is asserted, in which case the wait times are 12×100 longer. WTIME is programmed as a 2's complement number. Upon power up, the wait time register is set to 0xFF.

Table 7. Wait Time Register

FIELD	BITS		DESCF	RIPTION	_
WTIME	7:0	REGISTER VALUE	WAIT TIME	TIME (WLONG = 0)	TIME (WLONG = 1)
		0xFF	1	2.72 ms	0.032 sec
		0xB6	74	200 ms	2.4 sec
		0x00	256	700 ms	8.3sec

NOTE: The Proximity Wait Time register should be configured before PEN is asserted.

Proximity Interrupt Threshold Register (0x08 - 0x0B)

The proximity interrupt threshold registers provide the values to be used as the high and low trigger points for the comparison function for interrupt generation. If the value generated by proximity channel crosses below the lower threshold specified, or above the higher threshold, an interrupt is signaled to the host processor.

Table 8. Proximity Interrupt Threshold Register

REGISTER	ADDRESS	BITS	DESCRIPTION
PILTL	0x08	7:0	Proximity low threshold lower byte
PILTH	0x09	7:0	Proximity low threshold upper byte
PIHTL	0x0A	7:0	Proximity high threshold lower byte
PIHTH	0x0B	7:0	Proximity high threshold upper byte



Persistence Register (0x0C)

The persistence register controls the filtering interrupt capabilities of the device. Configurable filtering is provided to allow interrupts to be generated after each ADC integration cycle or if the ADC integration has produced a result that is outside of the values specified by threshold register for some specified amount of time.

Table 9. Persistence Register

	7	6	5	4	3	2	1	0	
PERS		PPEF	IS			Rese	erved		Reset 0x00

FIELD	BITS	DESCRIPTION					
PPERS	7:4	Proximity interrupt	persistence. (Controls rate of proximity interrupt to the host processor.			
		FIELD VALUE	MEANING	INTERRUPT PERSISTENCE FUNCTION			
		0000		Every proximity cycle generates an interrupt			
		0001	1	1 proximity value out of range			
		0010	2	2 consecutive proximity values out of range			
		1111	15	15 consecutive proximity values out of range			
Reserved	3:0	Default setting is 0:	x00.				

Configuration Register (0x0D)

The configuration register sets the wait long time.

Table 10. Configuration Register

7 6 5 4 3 2 1 0

CONFIG Reserved WLONG Reserved 0x00

FIELD	BITS	DESCRIPTION
Reserved	7:2	Reserved. Write as 0.
WLONG	1	Wait Long. When asserted, the wait cycles are increased by a factor 12× from that programmed in the WTIME register.
Reserved	0	Reserved. Write as 0.

Proximity Pulse Count Register (0x0E)

The proximity pulse count register sets the number of proximity pulses that will be transmitted. PPULSE defines the number of pulses to be transmitted at a 62.5-kHz rate.

Table 11. Proximity Pulse Count Register

PPULSE PPULSE PPULSE PPULSE PPULSE PPULSE

FIELD	BITS	DESCRIPTION
PPULSE	7:0	Proximity Pulse Count. Specifies the number of proximity pulses to be generated.

TEXAS
ADVANCED
OPTOELECTRONIC
SOLUTIONS®

Control Register (0x0F)

The Control register provides four bits of control to the analog block. These bits control the diode drive current and diode selection functions.

Table 12. Control Register

CONTROL DDDIVE DDIODE DCAIN Decembed		1 0	2	3	4	5	6	7	
PDRIVE PDIODE PGAIN Reserved	Reset 0x00	Reserved	GAIN	PG	ODE	PDIC	IVE	PDR	CONTROL

FIELD	BITS	DESCRIPTION					
PDRIVE (Note 1)	7:6	Proximity LED Driv	Strength.				
		FIELD VALUE	LED STRENGTH — PDL = 0 LED STRENGTH — PDL = 1				
		00	100 mA	11.1 mA			
		01	50 mA	5.6 mA			
		10	25 mA	2.8 mA			
		11	12.5 mA	1.4 mA			
PDIODE	5:4	Proximity Diode Se	Selector.				
		FIELD VALUE	DIODE SELECTION				
		00	Proximity uses neither diode				
		01	Proximity uses the CH0 diode				
		10	Proximity uses the CH1 diode				
		11	Reserved — Do not write				
PGAIN	3:2	Proximity Gain.					
		FIELD VALUE	PROXIMITY	Y GAIN VALUE			
		00	1× gain				
		01	2× gain				
		10	4× gain				
		11	8× gain				
Reserved	1:0	Reserved.					

NOTE 1: LED STRENGTH values (italic) are nominal operating values. Specifications can be found in the Proximity Characteristics table.

Revision Register (0x11)

The Revision register shows the silicon revision number. It is a read-only register and shows the revision level of the silicon used internally.

Table 13. Revision Register

7 6 5 4 3 2 1 0

REVISION Reserved DIE_REV Reset Rev Num

FIELD	BITS	DESCRIPTION					
Reserved	7:4	Reserved	Bits read as 0				
DIE_REV	3:0	Die revision number	Die revision number				

ID Register (0x12)

The ID Register provides the value for the part number. The ID register is a read-only register.

Table 14. ID Register

	7	6	5	4	3	2	1	0	
ID [II)				Reset ID
FIELD	BITS				DESC	CRIPTION			
ID	7:0 Part number identification		0x32 = TMD26721						
טו		Fait Hullibel	art number identification					0x3B = TMD26723	

Status Register (0x13)

Reserved

7

6

Reserved.

The Status Register provides the internal status of the device. This register is read only.

5

Table 15. Status Register

STATUS	Reserved	PSAT	PINT	Reserved	PVALID	Reserved	0x00			
FIELD	BIT		DESCRIPTION							
Reserved	7	Reserved.	Reserved.							
PSAT	6	Proximity Sa	Proximity Saturation. Indicates that the proximity measurement saturated.							
PINT	5	Proximity In	Proximity Interrupt. Indicates that the device is asserting a proximity interrupt.							
Reserved	4:2	Reserved.	Reserved. Bits read as 0.							
PVALID	1	Proximity Va asserted.	Proximity Valid. Indicates that the proximity channel has completed an integration cycle after PEN has been asserted.							

Proximity Data Register (0x18 - 0x19h)

Proximity data is stored as a 16-bit value. To ensure the data is read correctly, a two-byte I²C read transaction should be utilized with auto increment protocol bits set in the command register. With this operation, when the lower byte register is read, the upper eight bits are stored into a shadow register, which is read by a subsequent read to the upper byte. The upper register will read the correct value even if the next ADC cycle ends between the reading of the lower and upper registers.

Table 16. PDATA Registers

	REGISTER	GISTER ADDRESS BITS		DESCRIPTION			
	PDATAL	0x18	7:0	Proximity data low byte			
4	PDATAH	PDATAH 0x19 7:0		Proximity data high byte			

Proximity Offset Register (0x1E)

The 8-bit proximity offset register provides compensation for proximity offsets caused by device variations, optical crosstalk, and other environmental factors. Proximity offset is a sign-magnitude value where the sign bit, bit 7, determines if the offset is negative (bit 7 = 0) or positive (bit 7 = 1). At power up, the register is set to 0x00. The magnitude of the offset compensation depends on the proximity gain (PGAIN), proximity LED drive strength (PDRIVE), and the number of proximity pulses (PPULSE). Because a number of environmental factors contribute to proximity offset, this register is best suited for use in an adaptive closed-loop control system. See available TAOS application notes for proximity offset register application information.

Table 17. Proximity Offset Register

	1	ь	5	4	3	2	ı	U		
POFFSET	SIGN			MAG	NITUDE			1	Reset 0x00	
	1	1								
FIELD	BIT		DESCRIPTION							
SIGN	7	Proximity O equal to 1.	Proximity Offset Sign. The offset sign shifts the proximity data negative when equal to 0 and positive when equal to 1.							
MAGNITUDE	6:0	Proximity Offset Magnitude. The offset magnitude shifts the proximity data positive or negative, depending on the proximity offset sign. The actual amount of the shift depends on the proximity gain (PGAIN), proximit LED drive strength (PDRIVE), and the number of proximity pulses (PPULSE).						ve, depending GAIN), proximity		

APPLICATION INFORMATION: HARDWARE

LED Driver Pin with Proximity Detection

In a proximity sensing system, the included IR LED can be pulsed with more than 100 mA of rapidly switching current, therefore, a few design considerations must be kept in mind to get the best performance. The key goal is to reduce the power supply noise coupled back into the device during the LED pulses. Averaging of multiple proximity samples is recommended to reduce the proximity noise.

The first recommendation is to use two power supplies; one for the device V_{DD} and the other for the IR LED. In many systems, there is a quiet analog supply and a noisy digital supply. By connecting the quiet supply to the V_{DD} pin and the noisy supply to the LEDA pin, the key goal can be met. Place a 1- μ F low-ESR decoupling capacitor as close as possible to the V_{DD} pin and another at the LEDA pin, and at least 10 μ F of bulk capacitance to supply the 100-mA current surge. This may be distributed as two 4.7 μ F capacitors.

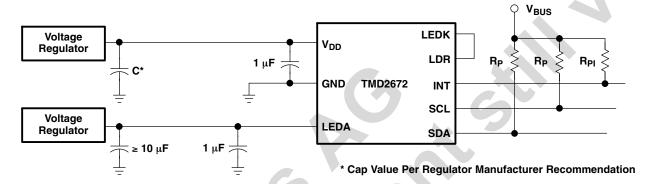


Figure 12. Proximity Sensing Using Separate Power Supplies

If it is not possible to provide two separate power supplies, the device can be operated from a single supply. A $22-\Omega$ resistor in series with the V_{DD} supply line and a $1-\mu F$ low ESR capacitor effectively filter any power supply noise. The previous capacitor placement considerations apply.

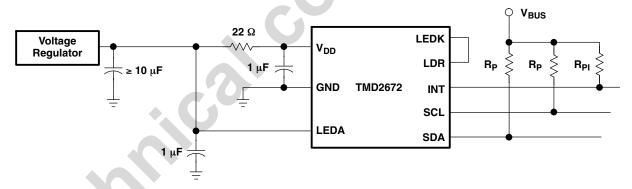


Figure 13. Proximity Sensing Using Single Power Supply

 V_{BUS} in the above figures refers to the I²C bus voltage which is either V_{DD} or 1.8 V. Be sure to apply the specified I²C bus voltage shown in the Available Options table for the specific device being used.

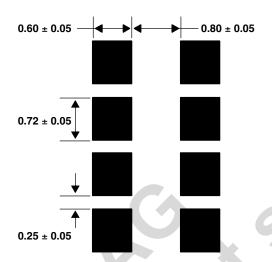
The I^2C signals and the Interrupt are open-drain outputs and require pull–up resistors. The pull-up resistor (R_P) value is a function of the I^2C bus speed, the I^2C bus voltage, and the capacitive load. The TAOS EVM running at 400 kbps, uses 1.5-k Ω resistors. A 10-k Ω pull-up resistor (R_{PI}) can be used for the interrupt line.

TEXAS
ADVANCED
OPTOELECTRONIC
SOLUTIONS®

APPLICATION INFORMATION: HARDWARE

PCB Pad Layout

Suggested PCB pad layout guidelines for the surface mount module are shown in Figure 14. Flash Gold is recommended surface finish for the landing pads.



NOTES: A. All linear dimensions are in mm.

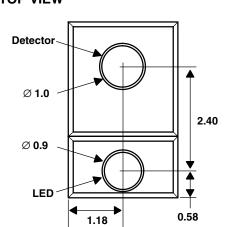
B. This drawing is subject to change without notice.

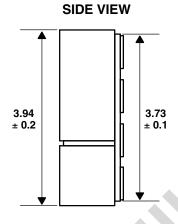
Figure 14. Suggested Module PCB Layout

PACKAGE INFORMATION

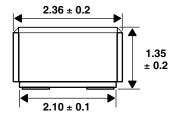
MODULE TOP VIEW

Dual Flat No-Lead

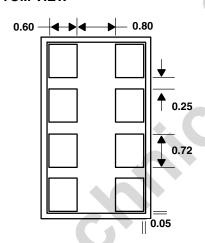




END VIEW



BOTTOM VIEW



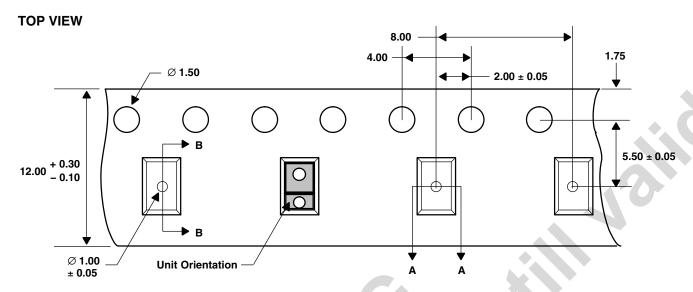


- NOTES: A. All linear dimensions are in millimeters. Dimension tolerance is $\pm\,0.05$ mm unless otherwise noted.
 - B. Contacts are copper with NiPdAu plating.
 - C. This package contains no lead (Pb).
 - D. This drawing is subject to change without notice.

Figure 15. Module Packaging Configuration

TEXAS
ADVANCED
OPTOELECTRONIC
SOLUTIONS®

CARRIER TAPE AND REEL INFORMATION





- NOTES: A. All linear dimensions are in millimeters. Dimension tolerance is $\pm\,0.10$ mm unless otherwise noted.
 - B. The dimensions on this drawing are for illustrative purposes only. Dimensions of an actual carrier may vary slightly.
 - C. Symbols on drawing A_0 , B_0 , and K_0 are defined in ANSI EIA Standard 481–B 2001.
 - D. Each reel is 330 millimeters in diameter and contains 2500 parts.
 - E. TAOS packaging tape and reel conform to the requirements of EIA Standard 481-B.
 - F. In accordance with EIA standard, device pin 1 is located next to the sprocket holes in the tape.
 - G. This drawing is subject to change without notice.

Figure 16. Module Carrier Tape

SOLDERING INFORMATION

The module has been tested and has demonstrated an ability to be reflow soldered to a PCB substrate. The process, equipment, and materials used in these test are detailed below.

The solder reflow profile describes the expected maximum heat exposure of components during the solder reflow process of product on a PCB. Temperature is measured on top of component. The components should be limited to a maximum of three passes through this solder reflow profile.

Table 18. Solder Reflow Profile

PARAMETER	REFERENCE	DEVICE		
Average temperature gradient in preheating		2.5°C/sec		
Soak time	t _{soak}	2 to 3 minutes		
Time above 217°C (T ₁)	t ₁	Max 60 sec		
Time above 230°C (T ₂)	t ₂	Max 50 sec		
Time above T _{peak} -10°C (T ₃)	t ₃	Max 10 sec		
Peak temperature in reflow	T _{peak}	260°C		
Temperature gradient in cooling		Max -5°C/sec		

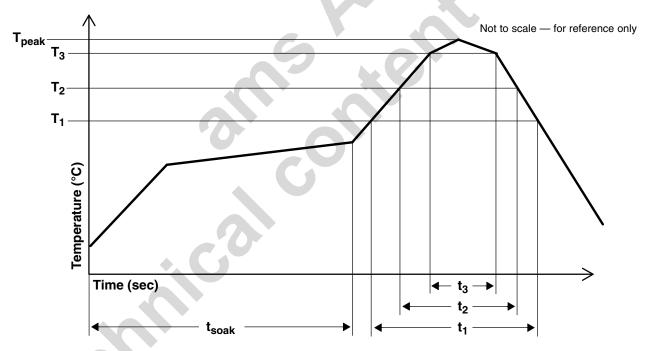


Figure 17. Solder Reflow Profile Graph

STORAGE INFORMATION

Moisture Sensitivity

Optical characteristics of the device can be adversely affected during the soldering process by the release and vaporization of moisture that has been previously absorbed into the package. To ensure the package contains the smallest amount of absorbed moisture possible, each device is dry-baked prior to being packed for shipping. Devices are packed in a sealed aluminized envelope called a moisture barrier bag with silica gel to protect them from ambient moisture during shipping, handling, and storage before use.

The Moisture Barrier Bags should be stored under the following conditions:

Temperature Range < 40°C Relative Humidity < 90%

Total Time No longer than 12 months from the date code on the aluminized envelope if

unopened.

Rebaking of the reel will be required if the devices have been stored unopened for more than 12 months and the Humidity Indicator Card shows the parts to be out of the allowable moisture region.

Opened reels should be used within 168 hours if exposed to the following conditions:

Temperature Range < 30°C Relative Humidity < 60%

If rebaking is required, it should be done at 50°C for 12 hours.

The Module has been assigned a moisture sensitivity level of MSL 3.



PRODUCTION DATA — information in this document is current at publication date. Products conform to specifications in accordance with the terms of Texas Advanced Optoelectronic Solutions, Inc. standard warranty. Production processing does not necessarily include testing of all parameters.

LEAD-FREE (Pb-FREE) and GREEN STATEMENT

Pb-Free (RoHS) TAOS' terms *Lead-Free* or *Pb-Free* mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TAOS Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br) TAOS defines *Green* to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material).

Important Information and Disclaimer The information provided in this statement represents TAOS' knowledge and belief as of the date that it is provided. TAOS bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TAOS has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TAOS and TAOS suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

NOTICE

Texas Advanced Optoelectronic Solutions, Inc. (TAOS) reserves the right to make changes to the products contained in this document to improve performance or for any other purpose, or to discontinue them without notice. Customers are advised to contact TAOS to obtain the latest product information before placing orders or designing TAOS products into systems.

TAOS assumes no responsibility for the use of any products or circuits described in this document or customer product design, conveys no license, either expressed or implied, under any patent or other right, and makes no representation that the circuits are free of patent infringement. TAOS further makes no claim as to the suitability of its products for any particular purpose, nor does TAOS assume any liability arising out of the use of any product or circuit, and specifically disclaims any and all liability, including without limitation consequential or incidental damages.

TEXAS ADVANCED OPTOELECTRONIC SOLUTIONS, INC. PRODUCTS ARE NOT DESIGNED OR INTENDED FOR USE IN CRITICAL APPLICATIONS IN WHICH THE FAILURE OR MALFUNCTION OF THE TAOS PRODUCT MAY RESULT IN PERSONAL INJURY OR DEATH. USE OF TAOS PRODUCTS IN LIFE SUPPORT SYSTEMS IS EXPRESSLY UNAUTHORIZED AND ANY SUCH USE BY A CUSTOMER IS COMPLETELY AT THE CUSTOMER'S RISK.

LUMENOLOGY, TAOS, the TAOS logo, and Texas Advanced Optoelectronic Solutions are registered trademarks of Texas Advanced Optoelectronic Solutions Incorporated.

